

OCXO Part No.: OS560-1005-010

Issue 2, 6th May 2022

Features

- Temperature stability ± 20 ppb
- Low phase noise
- Frequency 10.00MHz
- The flexible nature of the design means that variations to suit almost any application can be developed to meet individual customer requirements



Option C

- Temperature stability: ± 20 ppb over $(-40 \text{ to } 70)^\circ\text{C}$
- Output: Sinewave 0dBm nominal
- Voltage: 5.0V
- Warm up current: 520mA
- Quiescent current: 220mA

Phase Noise (typical)

- $F_0+10\text{Hz}$ -130 dBc/Hz
- $F_0+100\text{Hz}$ -150 dBc/Hz
- $F_0+1\text{KHz}$ -160 dBc/Hz
- $F_0+10\text{KHz}$ -168 dBc/Hz
- $F_0+100\text{KHz}$ -175 dBc/Hz

Voltage / Load change

- $\pm 5\%$ supply voltage change: ± 2 ppb
- $\pm 10\%$ load change: ± 10 ppb

Ageing

After 30 days continuous operation:

- Per day: ± 0.1 ppb max.
- Per year: ± 50 ppb max.
- Warm up time: 5 minutes to within 0.1ppm

Voltage Trim

- ± 0.5 ppm minimum
- Trim impedance 50K Ω

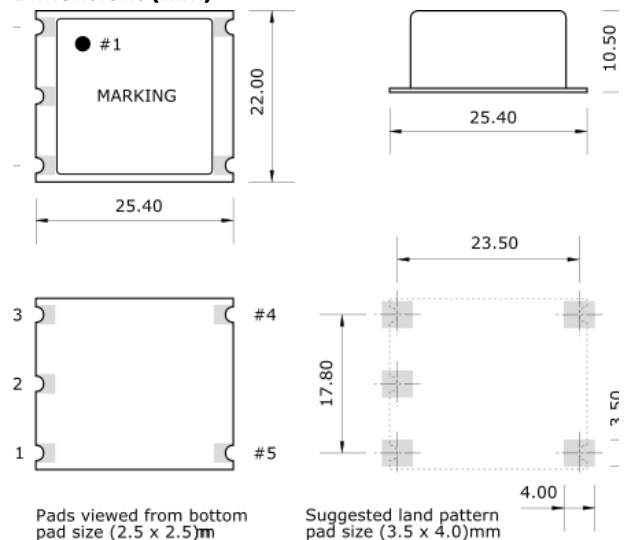
Reference Options

- 3.0V or 4.5V

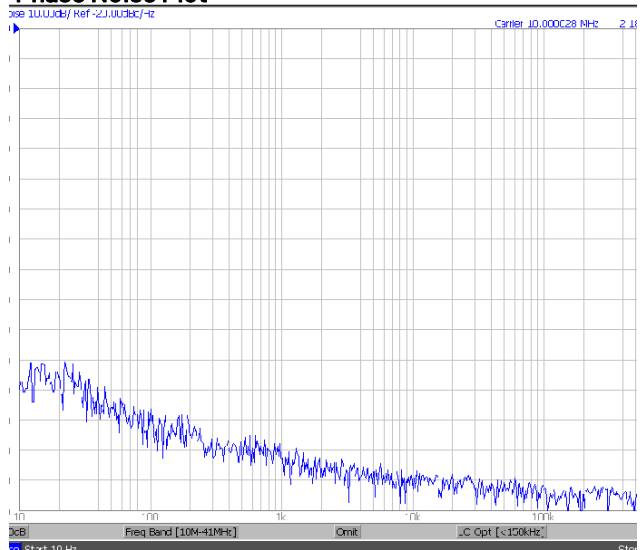
Environmental

- Electrostatic-Sensitive Device (ESD)
- Storage Temperature Range: $(-40 \text{ to } +125)^\circ\text{C}$
- Mechanical shock: MIL standard 202F, method 213, condition J
- Thermal shock: MIL standard 202F, method 107, condition A
- Vibration: MIL standard 202F, method 204, condition B

Dimensions (mm)



Phase Noise Plot



- Solderability: 5 seconds maximum at 230°C
- 3 seconds maximum at 350°C

Compliance

- RoHS Status (2011/65/EU) - Compliant
- REACH Status - Compliant

Packaging

- Pack Style: Bulk

Ordering Information

- OCXO Part No.: OS560-1005-010
- Frequency: 10.00MHz
- Stability/Output/Voltage: Option C

Test Circuit - Sinewave

